



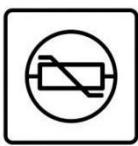
ESD



TVS



TSS



MOV



GDT



PLED

## 5N06S-MS

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### Product specification

## Description

The 5N06S-MS is the high cell density trenched N-ch MOSFETs, which provides excellent RDSON and efficiency for most of the small power switching and load switch applications.

The 5N06S-MS meet the RoHS and Green Product requirement with full function reliability approved.

## Product Summary

<b>BVDSS</b>	60V
<b>RDSON</b>	80mΩ
<b>ID</b>	5A

## FEATURE

- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

## Reference News

PACKAGE OUTLINE	PIN CONFIGURATION	Marking
 SOT-223		

## Absolute Maximum Ratings ( $T_A=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Max.	Units
$V_{DSS}$	Drain-Source Voltage	60	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Continuous Drain Current	$T_A = 25^\circ\text{C}$	A
		$T_A = 100^\circ\text{C}$	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>	12	A
$P_D$	Power Dissipation	$T_A = 25^\circ\text{C}$	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	83	°C/W
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	°C

**Electrical Characteristics** (T<sub>J</sub>=25°C unless otherwise specified)

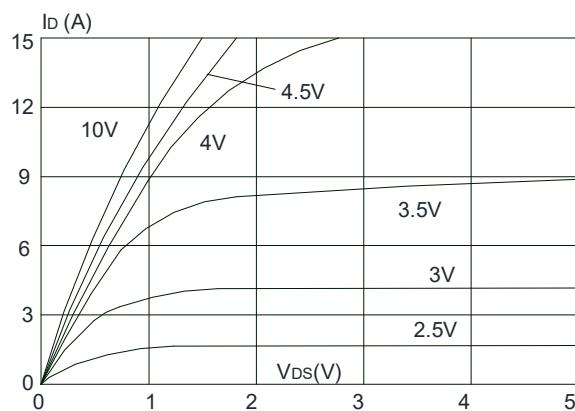
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V,	-	-	1.0	μA
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	-	-	±100	nA
<b>On Characteristics</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.4	2.0	V
R <sub>DS(on)</sub>	Static Drain-Source on-Resistance note2	V <sub>GS</sub> =10V, I <sub>D</sub> =3A	-	80	100	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =2A	-	90	120	
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f= 1.0MHz	-	350	-	pF
C <sub>oss</sub>	Output Capacitance		-	29	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	23	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =30V, I <sub>D</sub> =3A, V <sub>GS</sub> = 10V	-	9	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	1.5	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	2	-	nC
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DD</sub> =30V, I <sub>D</sub> =2A, R <sub>GEN</sub> =3Ω, V <sub>GS</sub> =10V	-	5	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	7	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	37	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	22	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current	-	-	5	-	A
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current	-	-	12	-	A
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> =3A	-	-	1.2	V

**Notes:** 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

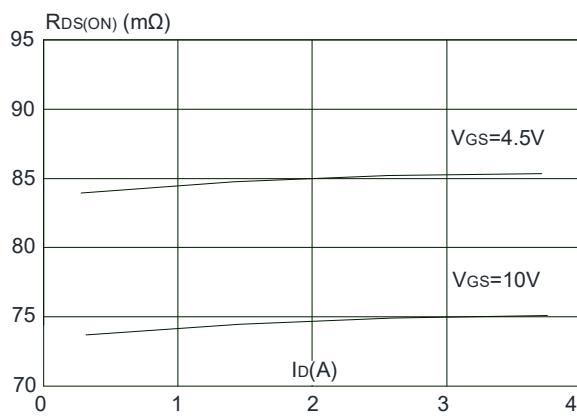
2. Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%

## Typical Performance Characteristics

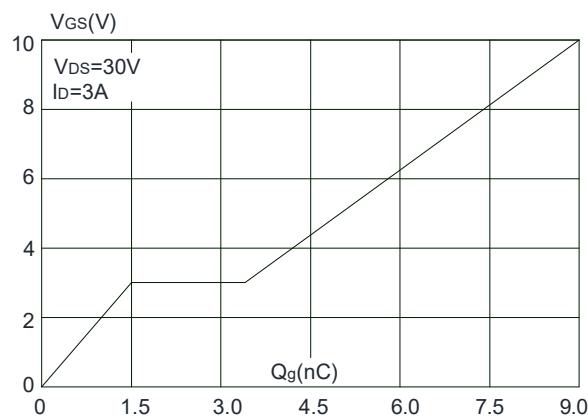
**Figure1:** Output Characteristics



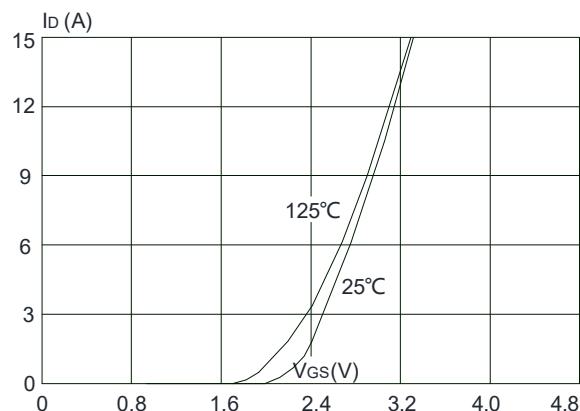
**Figure 3:** On-resistance vs. Drain Current



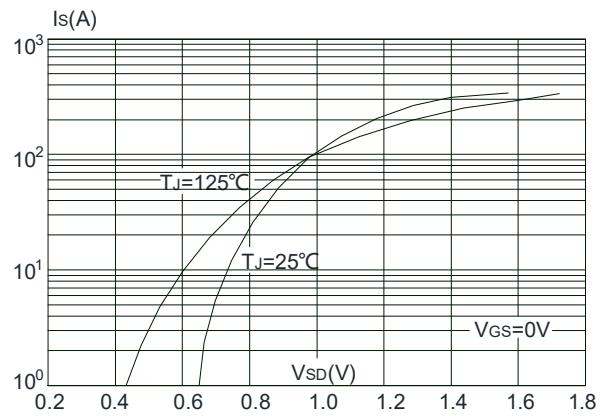
**Figure 5:** Gate Charge Characteristics



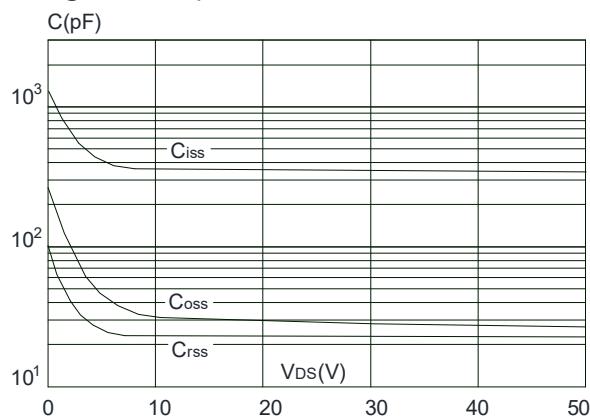
**Figure 2:** Typical Transfer Characteristics



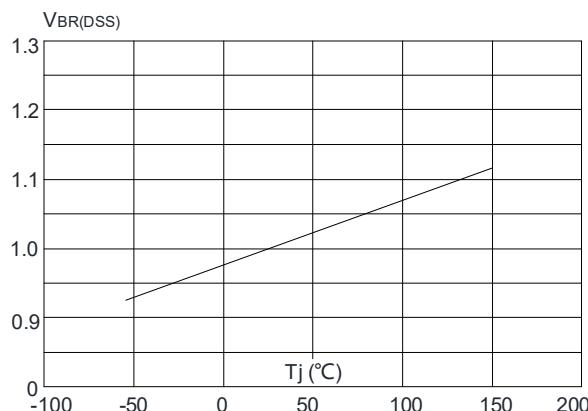
**Figure 4:** Body Diode Characteristics



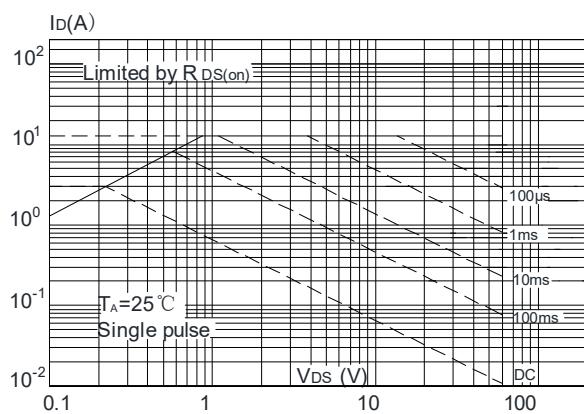
**Figure 6:** Capacitance Characteristics



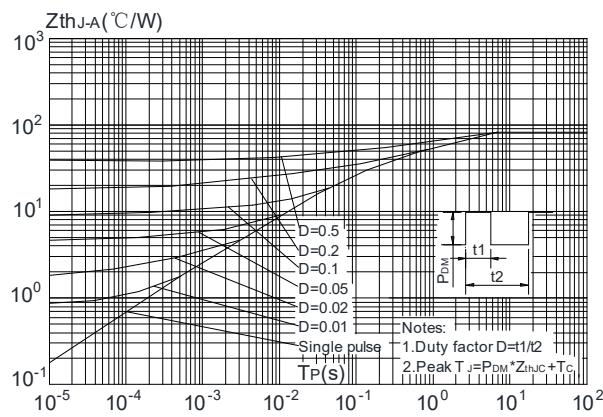
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



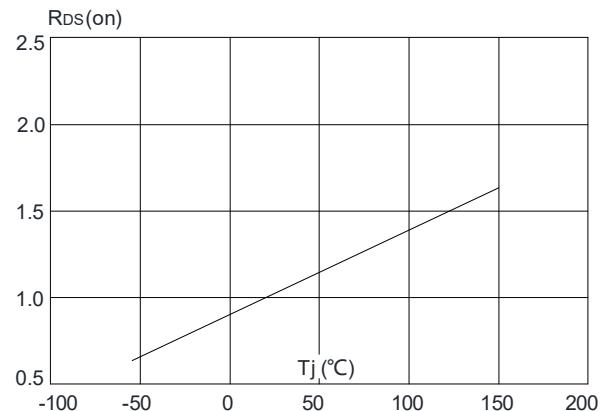
**Figure 9:** Maximum Safe Operating Area



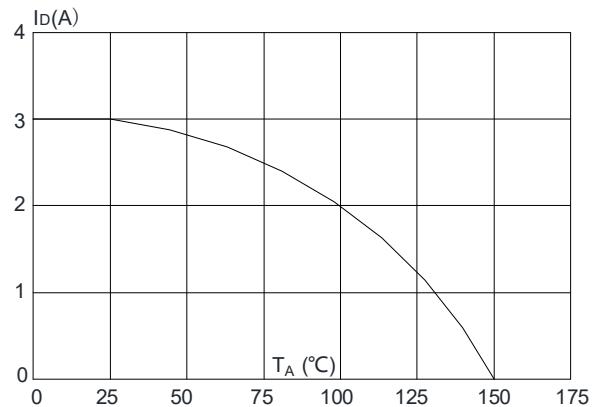
**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

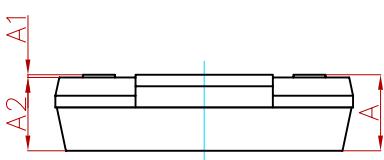
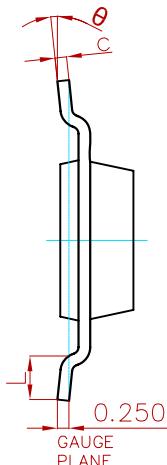
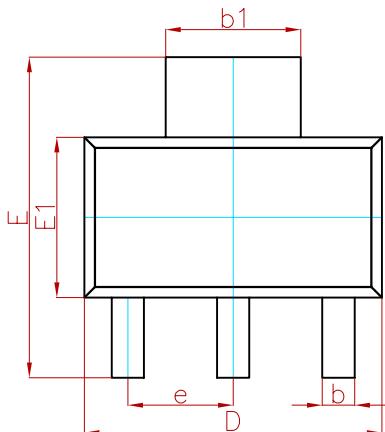


**Figure 8:** Normalized on Resistance vs. Junction Temperature

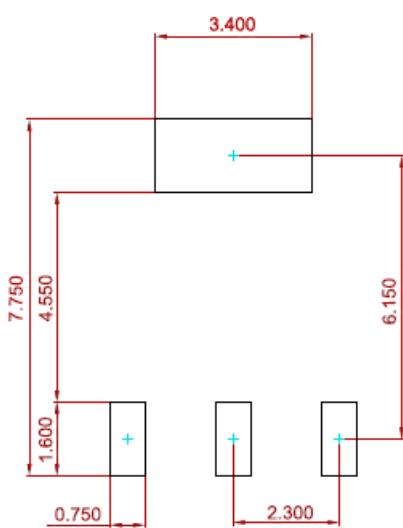


**Figure 10:** Maximum Continuous Drain Current vs. Ambient Temperature



**PACKAGE MECHANICAL DATA**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	—	1.800	—	0.071
A1	0.020	0.100	0.001	0.004
A2	1.500	1.700	0.059	0.067
b	0.660	0.840	0.026	0.033
b1	2.900	3.100	0.114	0.122
c	0.230	0.350	0.009	0.014
D	6.300	6.700	0.248	0.264
E	6.700	7.300	0.264	0.287
E1	3.300	3.700	0.130	0.146
e	2.300(BSC)		0.091(BSC)	
L	0.750	—	0.030	—
θ	0°	10°	0°	10°

**Suggested Pad Layout**

**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.050\text{mm}$ .
3. The pad layout is for reference purposes only.

**REEL SPECIFICATION**

P/N	PKG	QTY
5N06S-MS	SOT-223	2500

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